SCAS643B - SEPTEMBER 2000 REVISED JULY 2002

 General-Purpose and PCI-X 1:4 Clock Buffer

Operating Frequency: 0 MHz to 140 MHz

Low Output Skew: <100 ps</li>

- Distributes One Clock Input to One Bank of Four Outputs
- Output Enable Control That Drives Outputs Low When OE Is Low
- Operates From Single 3.3-V Supply
- 8-Pin TSSOP Package

#### 

TSSOP PW PACKAGE

### description

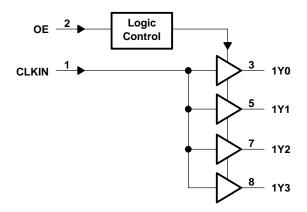
The CDCV304 is a high-performance, low-skew, general-purpose and PCI-X clock buffer. It distributes one input clock signal (CLKIN) to the output clocks (1Y[0:3]). It is specifically designed for use with PCI-X applications. The CDCV304 operates at 3.3 V.

The CDCV304 is characterized for operation from –40°C to 85°C for automotive and industrial applications.

### **FUNCTION TABLE**

INPUTS		OUTPUT
CLKIN	OE	1Y (0:3)
L	L	L
Н	L	L
L	Н	L
Н	Н	Н

### functional block diagram





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### **Terminal Functions**

TERM	IINAL	1/0	DESCRIPTION	
NAME	NO.	1/0	DESCRIPTION	
1Y[0-3]	3, 5, 7, 8	0	Buffered output clocks	
CLKIN	1	I	nput reference frequency	
GND	4	Power	Ground	
OE	2	I	Outputs enable control	
V <sub>DD</sub> 3.3V	6	Power	3.3-V supply	

### absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Supply voltage range, V <sub>DD</sub>	0.5 V to 4.3 V
Input voltage range, V <sub>I</sub> (see Notes 1 and 2)	$\dots$ -0.5 V to V <sub>DD</sub> + 0.5 V
Output voltage range, V <sub>O</sub> (see Notes 1 and 2)	$-0.5 \text{ V to V}_{DD} + 0.5 \text{ V}$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{DD}$ )	±50 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>DD</sub> )	±50 mA
Continuous total output current, $I_O$ ( $V_O = 0$ to $V_{DD}$ )	±50 mA
Package thermal impedance, $\theta_{JA}$ (see Note 3): PW package	230.5°C/W
Storage temperature range, T <sub>stg</sub>	65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
  - 2. This value is limited to 4.6 V maximum.
  - 3. The package thermal impedance is calculated in accordance with JESD 51.

### recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V <sub>DD</sub>	3	3.3	3.6	V
High-level input voltage, VIH	0.7×V <sub>DD</sub>			V
Low-level input voltage, V <sub>IL</sub>			0.3×V <sub>DD</sub>	V
Input voltage, V <sub>I</sub>	0		$V_{DD}$	V
High-level output current, I <sub>OH</sub>			-24	mA
Low-level output current, I <sub>OL</sub>			24	mA
Operating free-air temperature, T <sub>A</sub>	-40		85	°C

### timing requirements over recommended ranges of supply voltage and operating free-air temperature

		MIN	NOM MAX	UNIT
f <sub>clk</sub>	Clock frequency	0	140	MHz



### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP <sup>†</sup>	MAX	UNIT
VIK	Input voltage	$V_{DD} = 3 V$ ,	I <sub>I</sub> = -18 mA			-1.2	V
		$V_{DD} = min to max,$	$I_{OH} = -1 \text{ mA}$	V <sub>DD</sub> -0.2			
∨он	High-level output voltage	$V_{DD} = 3 V$ ,	$I_{OH} = -24 \text{ mA}$	2			V
		V <sub>DD</sub> = 3 V,	$I_{OH} = -12 \text{ mA}$	2.4			
		$V_{DD} = min to max,$	I <sub>OL</sub> = 1 mA			0.2	V
VOL	Low-level output voltage	V <sub>DD</sub> = 3 V,	I <sub>OL</sub> = 24 mA			0.8	
		V <sub>DD</sub> = 3 V,	I <sub>OL</sub> = 12 mA			0.55	
10	High-level output current	$V_{DD} = 3 V$ ,	V <sub>O</sub> = 1 V	-50			mA
ЮН		$V_{DD} = 3.3 \text{ V},$	V <sub>O</sub> = 1.65 V		-55		
1	Low lovel output ourrent	$V_{DD} = 3 V$ ,	V <sub>O</sub> = 2 V	60			mA
IOL	Low-level output current	V <sub>DD</sub> = 3.3 V,	V <sub>O</sub> = 1.65 V		70		IIIA
Ιį	Input current	$V_I = V_O \text{ or } V_{DD}$				±5	μΑ
I <sub>DD</sub>	Dynamic current, See Figure 5	f = 67 MHz				37	mA
Ci	Input capacitance	$V_{DD} = 3.3 \text{ V},$	V <sub>I</sub> = 0 V or V <sub>DD</sub>		3		pF
Со	Output capacitance	$V_{DD} = 3.3 \text{ V},$	V <sub>I</sub> = 0 V or V <sub>DD</sub>		3.2		pF

<sup>&</sup>lt;sup>†</sup> All typical values are at respective nominal V<sub>DD</sub> and 25°C.

## switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C<sub>L</sub> = 10 pF, V<sub>DD</sub> = 3.3 V $\pm$ 0.3 V (see Note 6 and Figures 1 and 2)

	PARAMETER	TEST CONDITIONS	MIN	TYP <sup>†</sup>	MAX	UNIT	
<sup>t</sup> PLH	High-to-low propagation delay	See Figures 4 and 2	1.8	2.5	3	ns	
tPHL	Low-to-high propagation delay	See Figures 1 and 2	1.8	2.4	3	ns	
tsk(o)	Output skew (see Note 4)			50	100	ps	
tsk(p)	Pulse skew	$V_{IH} = V_{DD}$ , $V_{IL} = 0$ V			150	ps	
tsk(pr)	Process skew			0.2	0.3	ns	
tsk(pp)	Part-to-part skew			0.25	0.4	ns	
т	Ol Khinh tine One Figure 4	66 MHz	6				
T <sub>high</sub>	CLK high time, See Figure 4	140 MHz	3			ns	
T. Oliklassiissa Osa Fissas 4	Cl K low time See Figure 4	66 MHz	6				
T <sub>low</sub>	CLK low time, See Figure 4	140 MHz	3			ns	
t <sub>r</sub>	Output rise slew rate <sup>‡</sup>	0.2V <sub>DD</sub> to 0.6V <sub>DD</sub>	1.5	2.7	4	V/ns	
t <sub>f</sub>	Output fall slew rate <sup>‡</sup>	0.6V <sub>DD</sub> to 0.2V <sub>DD</sub>	1.5	2.7	4	V/ns	

<sup>&</sup>lt;sup>†</sup> All typical values are at respective nominal V<sub>DD</sub>.

NOTE 4: The  $t_{Sk(0)}$  specification is only valid for equal loading of all outputs.



<sup>‡</sup> This symbol is according to PCI-X terminology.

### PARAMETER MEASUREMENT INFORMATION

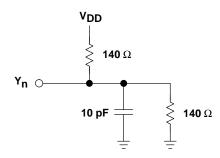


Figure 1. Test Load Circuit

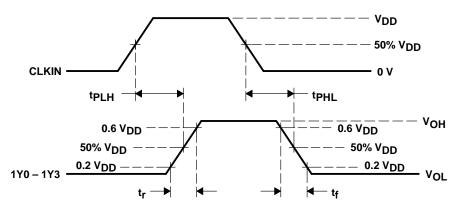


Figure 2. Voltage Thresholds for Propagation Delay (tpd) Measurements

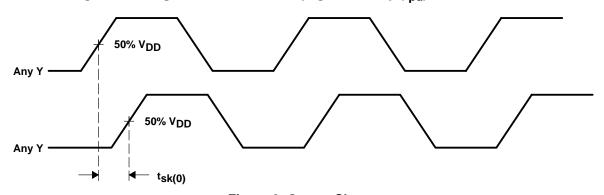
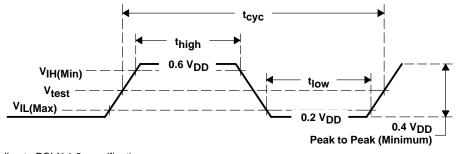


Figure 3. Output Skew

PARAMETER	VALUE	UNIT
V <sub>IH(Min)</sub>	0.5 V <sub>DD</sub>	٧
V <sub>IL(Max)</sub>	0.35 V <sub>DD</sub>	٧
V <sub>test</sub>	0.4 V <sub>DD</sub>	٧



NOTE: All parameters in Figure 4 are according to PCI-X 1.0 specifications.

Figure 4. Clock Waveform



### PARAMETER MEASUREMENT INFORMATION

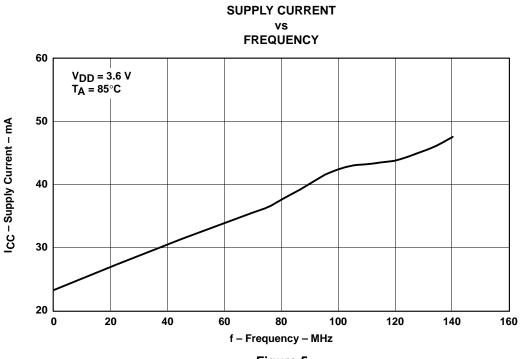
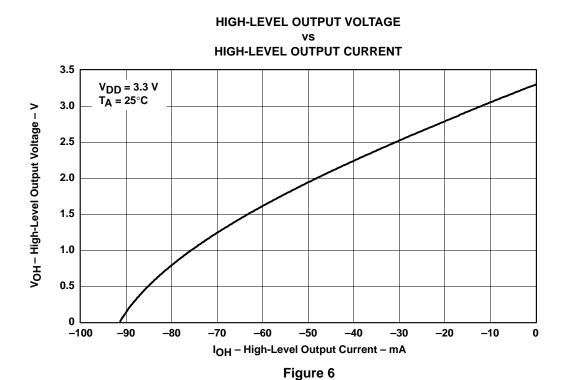


Figure 5





### PARAMETER MEASUREMENT INFORMATION

# LOW-LEVEL OUTPUT VOLTAGE vs LOW-LEVEL OUTPUT CURRENT

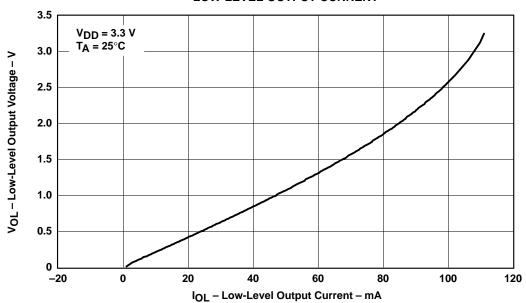


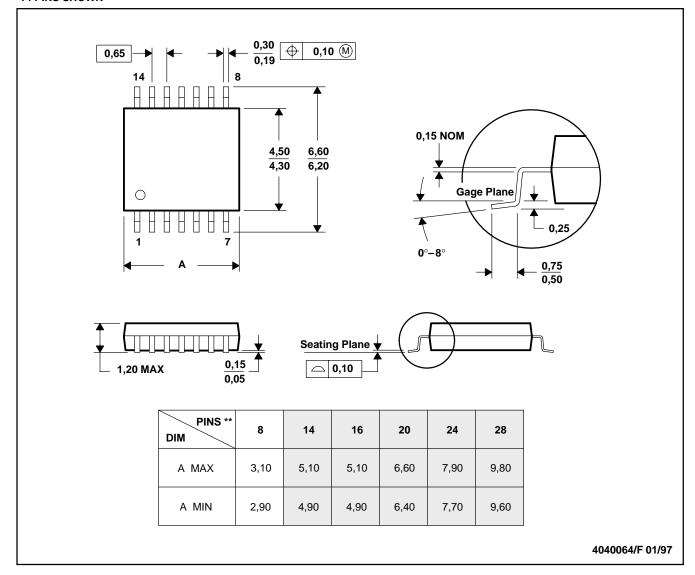
Figure 7

### **MECHANICAL DATA**

### PW (R-PDSO-G\*\*)

### 14 PINS SHOWN

### PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

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